

Search Notes

Application/Control No.

10/532,204

Examiner

Yuwen Pan

Applicant(s)/Patent under
Reexamination

SCHOULZ ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	575.1,90.3 ,347,344	2/25/2007	YP
379	455,446		
	454		
224	271,669		
	272,197		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/25/2007	YP